Unit: mm

TOSHIBA Transistor Silicon PNP / NPN Epitaxial Type (PCT Process)

# **HN4B101J**

# MOS Gate Drive Applications Switching Applications

- Small footprint due to a small and thin package
- High DC current gain :  $h_{FE}$  = 200 to 500 ( $I_{C}$  = -0.12 A)
- Low collector-emitter saturation: PNP  $V_{CE (sat)} = -0.20 \text{ V (max)}$

: NPN  $V_{CE (sat)} = 0.17 V (max)$ 

• High-speed switching : PNP  $t_f$  = 45 ns (typ.)

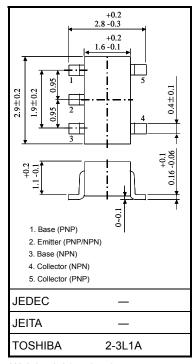
: NPN  $t_f = 50 \text{ ns (typ.)}$ 

### Maximum Ratings (Ta = 25°C)

Characteristic		Symbol	Rating		Unit	
		Symbol	PNP	NPN	Onit	
Collector-base voltage		$V_{CBO}$	-30	50	٧	
Collector-emitter voltage		V <sub>CEO</sub>	-30	30	V	
Emitter-base voltage		V <sub>EBO</sub>	-7	7	V	
Collector current	DC (Note 1)	I <sub>C</sub>	-1.0	1.2	Α	
	Pulse (Note 1)	I <sub>CP</sub>	-5.0	5.0	А	
Base current		Ι <sub>Β</sub>	-120	120	mA	
Collector power dissipation (t = 10 s)	Single-device operation	Pc (Note 2)	0.85		W	
Collector power dissipation (DC)	Single-device operation	Pc (Note 2)	0.55		W	
Junction temperature		Tj	150		°C	
Storage temperature range		T <sub>stg</sub>	-55 to 150		°C	

Note 1: Ensure that the channel temperature does not exceed 150°C during use of the device.

Note 2: Mounted on an FR4 board (glass-epoxy; 1.6 mm thick; Cu area, 645 mm<sup>2</sup>)



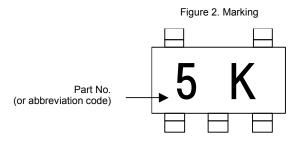
Weight: 0.014g (typ.)

Figure 1. Circuit Configuration
(Top View)

5

4

PNP
NPN
NPN
1
2
3



2005-03-28

## Electrical Characteristics (Ta = 25°C)

## **PNP**

Characteristic		Symbol	Test Condition	Min	Тур.	Max	Unit
Collector cut-off current		I <sub>CBO</sub>	$V_{CB} = -30 \text{ V}, I_E = 0$	_	_	-100	nA
Emitter cut-off current		I <sub>EBO</sub>	$V_{EB} = -7 \text{ V}, I_{C} = 0$	_	_	-100	nA
Collector-emitter bre	eakdown voltage	V (BR) CEO	$I_C = -10 \text{ mA}, I_B = 0$	-30	_	_	V
DC current gain		h <sub>FE</sub> (1)	$V_{CE} = -2 \text{ V}, I_{C} = -0.12 \text{ A}$	200	_	500	
		h <sub>FE</sub> (2)	$V_{CE} = -2 \text{ V}, I_{C} = -0.4 \text{ A}$	125	_	_	
Collector-emitter saturation voltage		V <sub>CE (sat)</sub>	$I_C = -0.4 \text{ A}, I_B = -13 \text{ mA}$	_	_	-0.20	V
Base-emitter saturat	tion voltage	V <sub>BE (sat)</sub>	$I_C = -0.4 \text{ A}, I_B = -13 \text{ mA}$	_	_	-1.10	V
Collector output capacitance		C <sub>ob</sub>	$V_{CB} = -10 \text{ V}, I_E = 0, f = 1 \text{MHz}$	_	7.8	_	pF
Switching time	Rise time	t <sub>r</sub>	See Figure 3 circuit diagram $V_{CC} \simeq -16~V,~R_L = 40~\Omega$ $-I_{B1} = I_{B2} = 13~mA$	_	40	_	ns
	Storage time	t <sub>stg</sub>		_	200	_	
	Fall time	t <sub>f</sub>		_	45	_	

#### **NPN**

Cha	racteristic	Symbol	Test Condition	Min	Тур.	Max	Unit
Collector cut-off current		I <sub>CBO</sub>	$V_{CB} = 50 \text{ V}, I_{E} = 0$	_	_	100	nA
Emitter cut-off current		I <sub>EBO</sub>	V <sub>EB</sub> = 7 V, I <sub>C</sub> = 0	_	_	100	nA
Collector-emitter breakdown voltage		V (BR) CEO	$I_C = 10 \text{ mA}, I_B = 0$	30	_	_	V
DC current gain		h <sub>FE</sub> (1)	V <sub>CE</sub> = 2 V, I <sub>C</sub> = 0.12 A	200	_	500	
		h <sub>FE</sub> (2)	V <sub>CE</sub> = 2 V, I <sub>C</sub> = 0.4 A	125	_	_	
Collector-emitter saturation voltage		V <sub>CE (sat)</sub>	$I_C = 0.4 \text{ A}, I_B = 13 \text{ mA}$	_	_	0.17	V
Base-emitter saturation voltage		V <sub>BE (sat)</sub>	$I_C = 0.4 \text{ A}, I_B = 13 \text{ mA}$	_	_	1.10	V
Collector output capacitance		C <sub>ob</sub>	V <sub>CB</sub> = 10 V, I <sub>E</sub> = 0, f = 1MHz	_	7.0	_	pF
Switching time	Rise time	t <sub>r</sub>	See Figure 4 circuit diagram $V_{CC} \simeq 16 \text{ V, R}_L = 40 \ \Omega$ $I_{B1} = -I_{B2} = 13 \text{ mA}$	_	45	_	ns
	Storage time	t <sub>stg</sub>		_	450	_	
	Fall time	t <sub>f</sub>			50		

Figure 3. Switching Time Test Circuit & Timing Chart

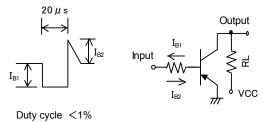
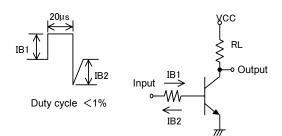
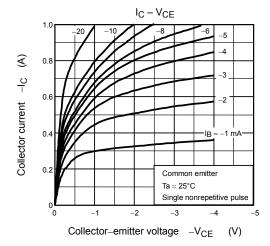
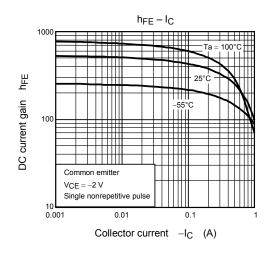


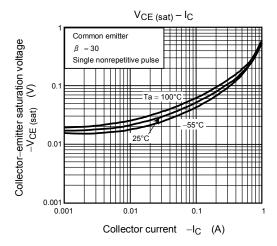
Figure 4. Switching Time Test Circuit & Timing Chart

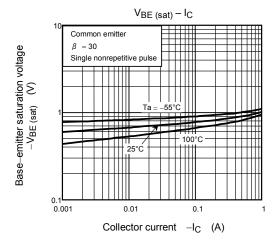


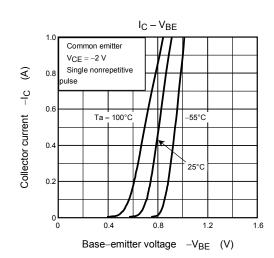
#### **PNP**

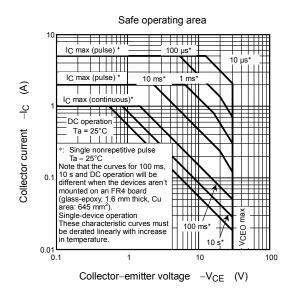




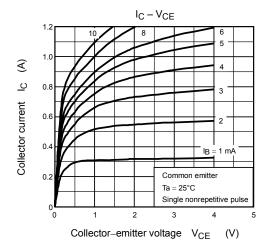


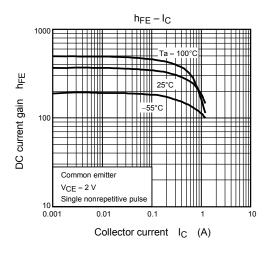


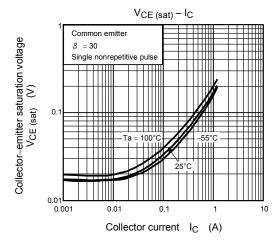


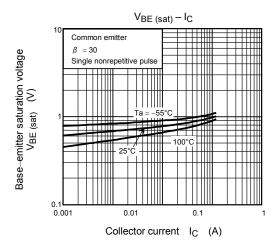


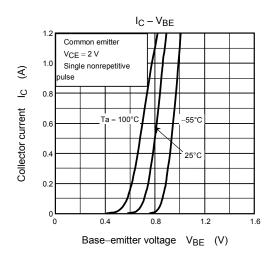
#### **NPN**

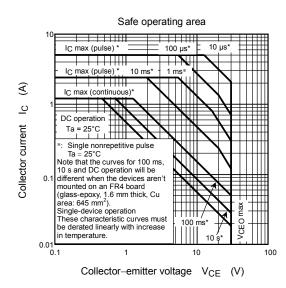




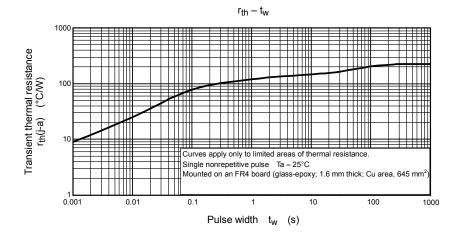




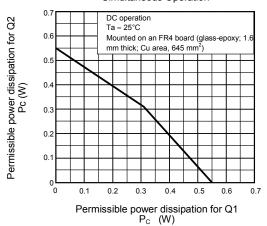




#### Common



# Permissible Power Dissipation for Simultaneous Operation



Collector power dissipation at single-device operation is 0.55  $\ensuremath{\mathrm{W}}.$ 

Collector power dissipation at single-device value at dual operation is 0.31 W.

Collector power dissipation at dual operation is set to 0.62 W.

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